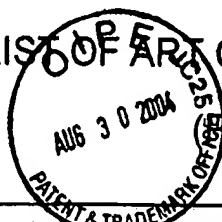


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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	JP 3151738	6/27/1991	JAPAN (Full Japanese Text)			Abst. only	
VP	JP 63225840	9/20/1988	JAPAN (Full Japanese Text)			Abst. only	
VP	JP 61107375	5/26/1986	JAPAN (Full Japanese Text)				X
VP	JP 60247683	12/7/1985	JAPAN (Full Japanese Text)				X

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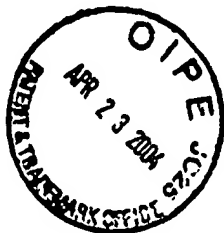
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CUSTOMER NO. 34610

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Date: March 18, 1999  
U.S. Natl. Phase  
Filing Date: July 11,  
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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	WO 00/64096	10-26-00	WIPO			X	
VP	DE 2641337A	03-16-78	Germany				X

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

VP	A. Menezes et al. "Handbook for Applied Cryptography" 1996 CRC PRESS XP002246921, ISBN: 0-8493-8523-7, pp. 543-550					

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International Filing  
Date: March 18, 1999  
U.S. Natl. Phase Filing  
Date: July 11, 2001GROUP  
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## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
VP	4,933,969	06-12-90	Marshall et al.	380	125	03-01-88

## U.S. PATENT APPLICATION PUBLICATIONS

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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
VP	JP 3-151738A	06-27-91	Japan			X	
VP	JP 8-185376A	07-16-96	Japan			X	
VP	JP 10-91705A	04-10-98	Japan			X	
VP	JP 63-255840A	09-20-88	Japan			X	
VP	JP 62-72243A	04-02-87	Japan			X	
VP	JP 2-259689A	10-22-90	Japan			X	
VP	JP 60-247683A	12-07-85	Japan			X	
VP	JP 61-107375A	05-26-86	Japan			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)


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				APPLICANT(S) <b>Yutaka YASUKURA</b>			
				FILING DATE International Filing Date: March 18, 1999 U.S. Natl. Phase Filing Date: July 11, 2001		GROUP <del>art unit</del> <div style="font-size: 1.5em; margin-top: 10px;">2132</div>	
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VP	JP 62-72243A	04-02-87	Japan				
VP	JP 2-259689A	10-22-90	Japan				
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EXAMINER	<i>Verlief Pennington</i>			DATE CONSIDERED <div style="font-size: 1.2em;">12/27/09</div>			

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